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U.S. UTILITY Patent Application

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**APPLICANT	S: Amano	Hiroshi; A	kasaki Isamu;	Kanek	o Yawara	; Yamada Nori	hiđe;	
Takeuchi Tetsı	ıya; Watanabe Sat	oshi;						ľ
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ITLE : Nitride so f same	emiconductor layer	rstructure	and a nitride	semico	nductor la	ser incorporati	ng a portion	
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		Assistant Examiner	Total Claims Print Claim for O.G
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TER	MINAL	PREPARED FOR ISSUE	Application Examiner
	DISCLAMER		ibited by the United States Code Title 35, in outside the U.S. Patent & Trademark